Editorial

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The collection of 14 articles published in this special issue has been authored by prominent researchers in applied probability that participated in the fourth International Workshop on Applied Probability, IWAP 2008. This workshop took place at the Technological University of Compiègne, Compiègne, France, on July 7–10, 2008. This event was co-sponsored by the Bernoulli Society, Conseil Régional de Picardie, Institute of Mathematical Statistics, Office of Naval Research, Société de Mathématiques Appliquées at Industrielles, Société Mathématique de France, Taylor & Francis Group and the Technological University of Compiègne.

The articles in this issue have been placed in the chronological order of the submission dates. The topics of the articles appearing in this special issue include: damage processes, level crossing in neural networks, Levy processes, Markov chain models, Markov population processes, matching common words in multiple random sequences, multivariate copulas, multivariate time series, Poisson approximations, probability approximations and inequalities, recursive trees, random trees, and scan statistics.

All articles published in this issue have undergone the usual refereeing process to maintain the high standards of regular published issues of the journal.

I would like to take this opportunity and thank the authors for submitting their articles to *Methodology and Computing in Applied Probability*, the associate editors and the referees for their dedication and hard work during the reviewing process.

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